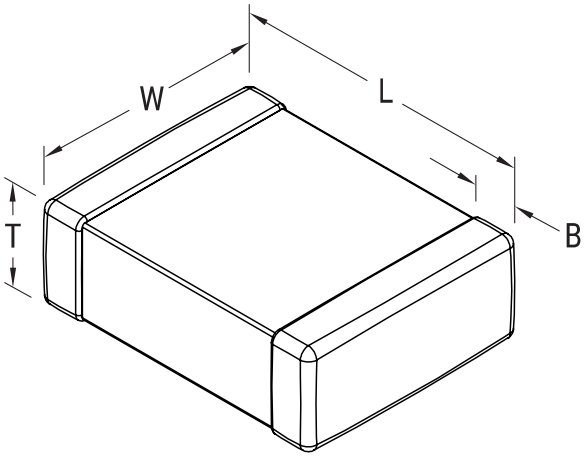
CDR33BX104AKUM

Aliases (C1210N104K5XML, CDR33BX104AKZM, CDR33BX104AKWM)

SMD Mil PRF55681, Ceramic, 0.1 uF, 10%, 50 VDC, BX, Ceramic Chips, MIL PRF 55681 Established Reliability, M (1%/1000 Hrs), 1210 / 3225



Click here for the 3D model.

General Information	
Series	SMD Mil PRF55681
Style	SMD Chip
Description	Ceramic Chips, MIL PRF 55681 Established Reliability
RoHS	No
Prop 65	**WARNING:** Cancer and reproductive harm - https://www.p65warnings.ca.gov./
Termination	Lead (SnPb)
Failure Rate	M (1%/1000 Hrs)
Testing and Reliability	MIL-PRF-55681
Qualifications	MIL-PRF-55681
Shelf Life	78 Weeks
MSL	1

Dimensions	
L	3.2mm +/-0.25mm
W	2.5mm +/-0.25mm
T	1.5mm MAX
B	0.5mm +/-0.25mm
Case Code (EIA / mm)	1210 / 3225

Packaging Specifications	
Packaging	Bulk, Bag
Packaging Quantity	25000

Specifications	
Capacitance	0.1 uF
Tolerance	10%
Voltage DC	50 VDC
Dielectric Withstanding Voltage	125 VDC
Temperature Range	-55/+125°C
Temp. Coefficient	BX
Dissipation Factor	2.5%
Insulation Resistance	100 GOhms

Statements of suitability for certain applications are based on our knowledge of typical operating conditions for such applications, but are not intended to constitute - and we specifically disclaim - any warranty concerning suitability for a specific customer application or use. This Information is intended for use only by customers who have the requisite experience and capability to determine the correct products for their application. Any technical advice inferred from this Information or otherwise provided by us with reference to the use of our products is given gratis, and we assume no obligation or liability for the advice given or results obtained.

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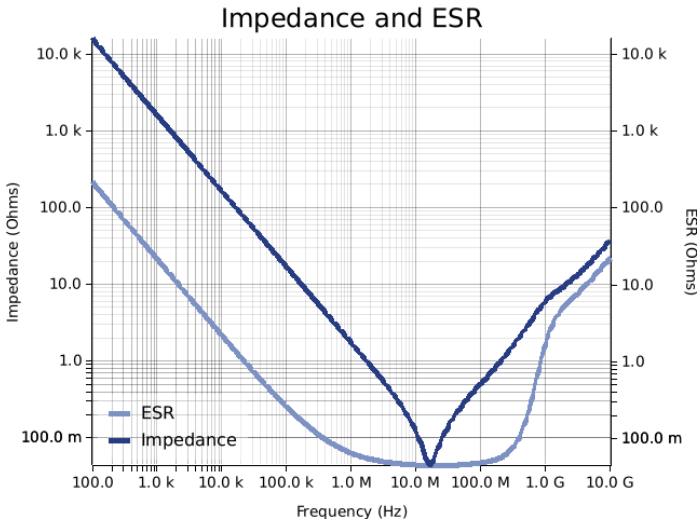
CDR33BX104AKUM

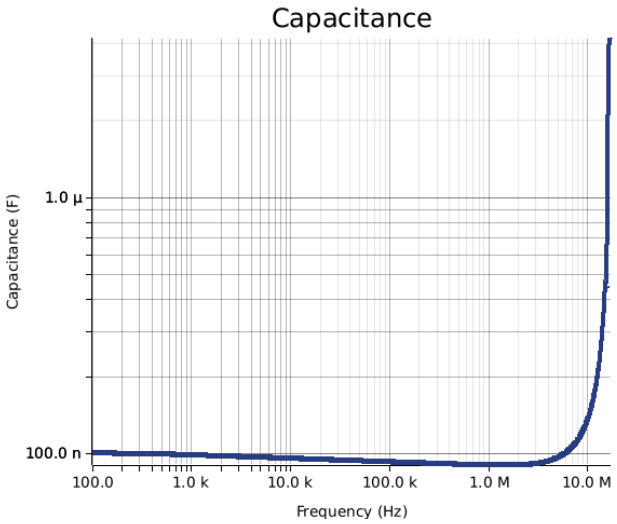
Aliases (C1210N104K5XML, CDR33BX104AKZM, CDR33BX104AKWM)

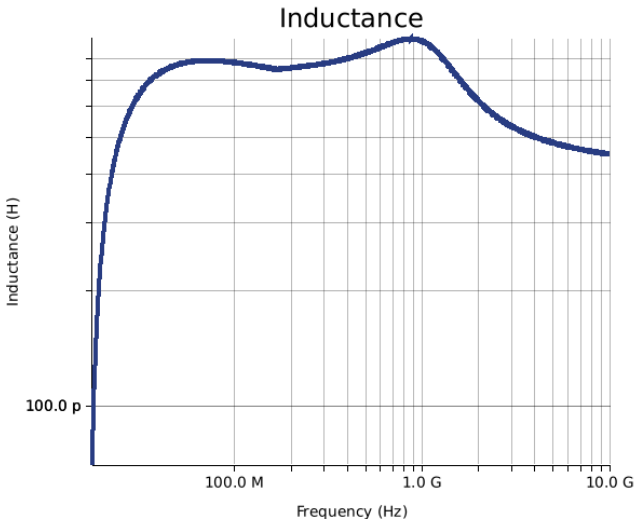
SMD Mil PRF55681, Ceramic, 0.1 uF, 10%, 50 VDC, BX, Ceramic Chips, MIL PRF 55681 Established Reliability, M (1%/1000 Hrs), 1210 / 3225

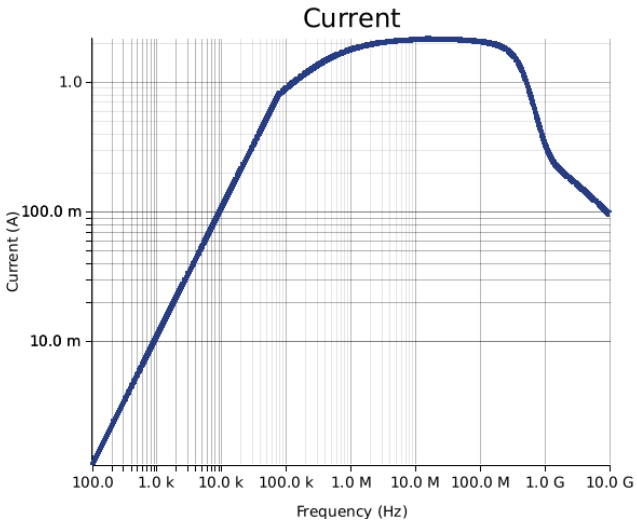
Simulations

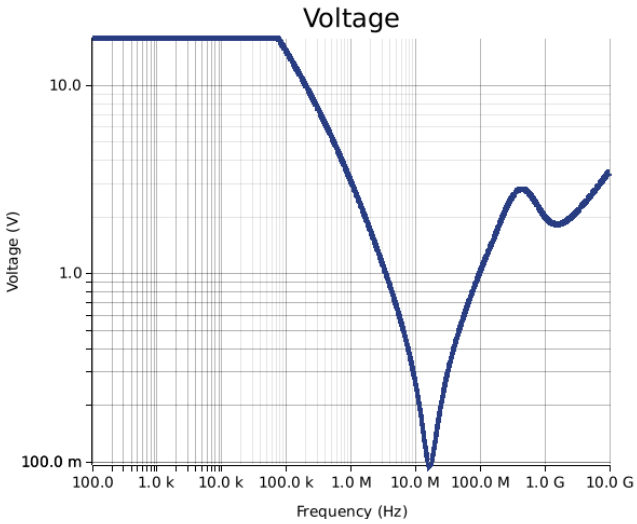
For the complete simulation environment please visit Y-SIM.

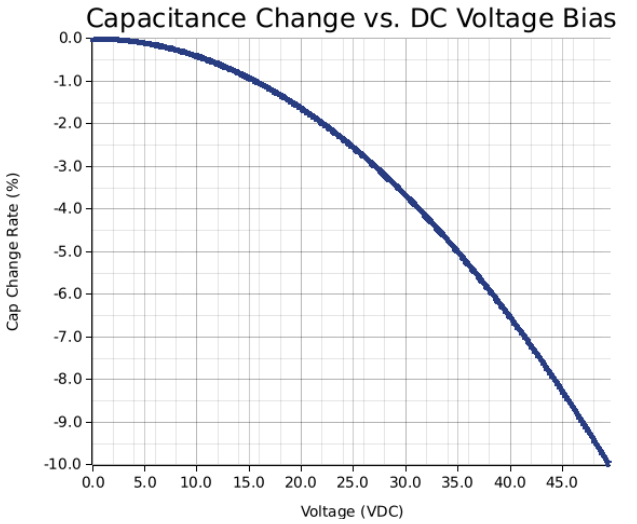










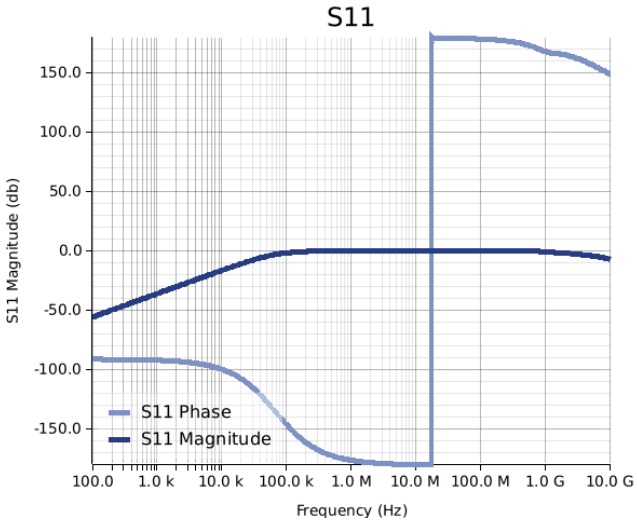


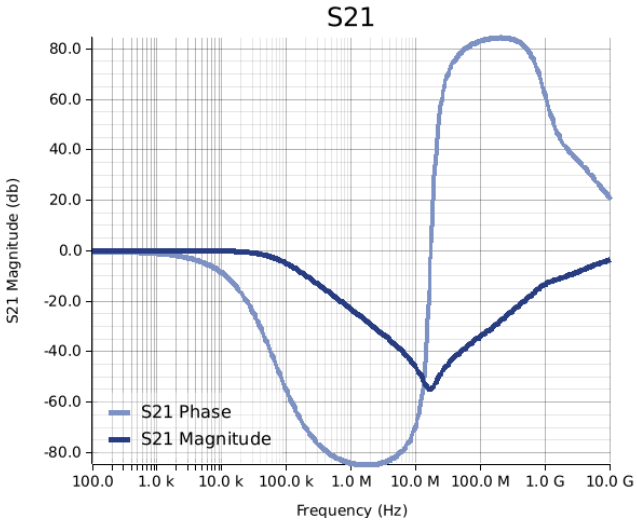
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These are simulations.
This is not a specification!

The responses shown represent the typical response for each part type. Specific responses may vary, depending on manufacturing variation affects of all parameters involved, including the specified tolerances applied to capacitance and unspecified variations of ESR, ESL, and leakage resistance.

The responses shown do not represent a specified or implied maximum capability of the device for all applications.

- The ESR used for ripple "Ripple Current/Voltage vs. Frequency" plots is the ESR at ambient temperature.
- The ESR in the "Temperature Rise vs. Ripple Current" plots is adjusted to each incremental temperature rise before the power and ripple current is calculated.
- The effects shown herein are based on measured data from a multiple part sample of the parts in question.
- Ripple capability of this device will be factored by thermal resistance (Rth) created by circuit traces (addi affects of all parameters involved, including the specified tolerances applied to capacitance and unspecified variations of ESR, ESL, and leakage resistance.
- The peak voltages generated in the "Temperature Rise vs. Combined Ripple Currents" plot are calculated for each frequency and are not combined with voltages generated at any other harmonics.
- Please consult with the catalog or field applications engineer for maximum capability of the device in specific applications.

All product information and data (collectively, the "Information") are subject to change without notice.

KEMET K-SIM is designed to simulate behavior of components with respect to frequency, ambient temperature, and DC bias levels. The responses shown represent the typical response for each part type. Specific responses may vary, depending on manufacturing variation effects of all parameters involved, including the specified tolerances applied to capacitance and unspecified variations of ESR, ESL, and leakage resistance.

All Information given herein is believed to be accurate and reliable, but is presented without guarantee, warranty, or responsibility of any kind, expressed or implied. Statements of suitability for certain applications are based on our knowledge of typical operating conditions for such applications, but are not intended to constitute – and we specifically disclaim – any warranty concerning suitability for a specific customer application or use. This Information is intended for use only by customers who have the requisite experience and capability to determine the correct products for their application. Any technical advice inferred from this Information or otherwise provided by us with reference to the use of our products is given gratis, and we assume no obligation or liability for the advice given or results obtained.

If you have any questions please contact K-SIM.

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